

<b>Notice of References Cited</b>	Application/Control No. 10/566,828	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner Ryan Lepisto	Art Unit 2883	Page 1 of 1

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*	C	US-2003/0081885	05-2003	Chen et al.	385/18
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	M	US-			

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**NON-PATENT DOCUMENTS**

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